



The Testcenter facility 'LoRa[®] Test Lab' within IMST GmbH is recognized by the LoRa[™] Alliance for testing in accordance to the LoRaWAN[™] Specification V1.0.4

Report for Certification by Similarity according to LoRaWAN™ V1.0.4

for the Device

"LHT65"

for the Customer

"Shenzhen Dragino Techno-logy Development co. LTD"

Jens Lerner Yavuz Turan

27th September, 2021

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Administrative Summary

Location: IMST GmbH, Test Centre, Kamp-Lintfort, Germany

Responsible Test Engineer: Yavuz Turan, Jens Lerner

Subject: Test of Conformance to LoRaWAN™ Specification V1.0.4

Company and Contact Information:

Shenzhen Dragino Technology Development co. LTD

Edwin Chen

No.8 CaiYunRoad, LongCheng Street, LongGang District

518116, Shenzhen

China

Checked Device: LHT65

Hardware version: LHT65 v1.4
Firmware version: LHT65 v1.9.0
Type and Version of used Stack: own

Original End-device identifier: LST Module

LoRa Device Class: A

LoRaWAN Specification version: V1.0.4

Certification requirements: LoRa End Device Certification by Similarity V1.1

Frequency band(s): 868 MHz
Type of Certification by Similarity:

Case 2: Certification of module variant from a certified module

Variant device differences to the referenced certified device:

- Same LoRa transceiver
- Same LoRa protocol SW version
- Same MCU Core
- Same Clock design and implementation

Brief description of the differences between the primary and the variant device

They are of same hardware architecture but different hardware layout for different application

Date: 27th September, 2021

The Test Report, No. 6210800 has the following conclusion:

The device fulfils the requirements.

Responsibility: / 1/ 1/ 1/ Approved:

Jens Lerne

Test Engineer

Quality Engineer

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